



Customer No. 22,852
Attorney Docket No. 03180.0338

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
)
Masao IWASE et al.)
) Group Art Unit: 2811
Application No.: 10/687,705)
) Examiner: Not yet assigned
Filed: October 20, 2003)
)
For: SEMICONDUCTOR WAFER)
AND A METHOD FOR)
MANUFACTURING A)
SEMICONDUCTOR WAFER)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§1.56 and 1.97(b), applicants bring to the Examiner's attention the documents listed on attached Form PTO-1449. Copies of the listed documents are attached. Applicants respectfully request that the Examiner consider the documents listed on attached Form PTO-1449 and indicate that they were considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits for the above-referenced application.

The following are listed on the accompanying PTO-1449 and are in a non-English language. English-language abstracts are attached.

1. Japanese Patent Laid-Open (Kokai) No. 2002-353080 - This document discloses a semiconductor wafer having an ID mark on the periphery thereof and a method of manufacturing such a semiconductor wafer. (Fig. 1 and lines 31-46 of the left portion of page 4).
2. Japanese Patent Laid-Open (Kokai) No. 2001-351835 - This document discloses a method to form a hole type dot mark in a semiconductor wafer. (Fig. 6 and lines 38-48 of the right portion of page 4).
3. Japanese Patent Laid-Open (Kokai) No. 2001-118757 - This document discloses a semiconductor wafer with which the dot mark was formed. (Fig. 11 and lines 9-14 of the left portion of page 5)
4. Japanese Patent Laid-Open (Kokai) No. 2000-223380 - This document discloses a semiconductor wafer by which marking was carried out to the notch portion. (Fig. 1 and lies 2-6 of the right portion of page 4).
5. Japanse Patent Laid-Open (Kokai) No. 2000-223382 - This document discloses the formation method of the minute dot mark excellent in visibility. (Fig. 3 and lines 23-33 of the left portion of page 4).

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claim in the application and applicants determine that the cited documents do not constitute "prior art" under United States law, applicants reserve the right to present to the Office the relevant facts and law regarding the

appropriate status of such documents. Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

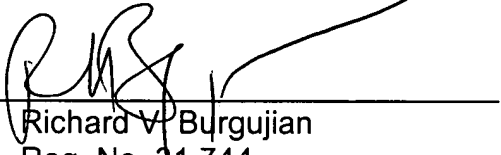
If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,
GARRETT & DUNNER, L.L.P.

Dated: March 17, 2004

By: _____


Richard V. Burgujian
Reg. No. 31,744

Enclosures
RVB/FPD/cma

INFORMATION DISCLOSURE CITATION

Atty. Docket No.	03180.0338	Application No.	10/687,705
Applicant	Masao IWASE et al.		
Filing Date	October 20, 2003	Group:	2811

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
2002-353080	12/06/2002	Japan			Abstract
2001-351835	12/21/2001	Japan			Abstract
2001-118757	04/27/2001	Japan			Abstract
2000-223380	08/11/2000	Japan			Abstract
2000-223382	08/11/2000	Japan			Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Date Considered
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	
Form PTO 1449	Patent and Trademark Office - U.S. Department of Commerce